Docket No.: 835.1026

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Shizuo Sumida, et al.

Serial No. TBA   Group Art Unit: TBA

Confirmation No. TBA

Filed: December 21, 2001   Examiner: TBA

For: CHARACTERISTIC VALUE IDENTIFICATION METHOD AND APPARATUS

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Before examination of the above-identified application, please amend the application as follows:

IN THE CLAIMS:

Please **AMEND** claim 6 as follows:

6. (ONCE AMENDED) The characteristic value identification method as claimed in claim 1, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

Please **ADD** the claims 19-22 as follows:

19. (NEW) The characteristic value identification method as claimed in claim 2, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

20. (NEW) The characteristic value identification method as claimed in claim 3, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

21. (NEW) The characteristic value identification method as claimed in claim 4, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

22. (NEW) The characteristic value identification method as claimed in claim 5, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

REMARKS

This Preliminary Amendment is submitted to improve the form of the claims as originally-filed.

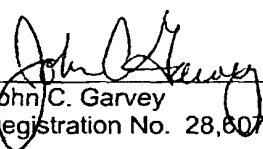It is respectfully requested that this Preliminary Amendment be entered in the above-referenced application.

If there are any additional fees associated with filing of this Preliminary Amendment, please charge the same to our Deposit Account No. 19-3935.

Respectfully submitted,

STAAS & HALSEY LLP

Date: _____12-24-01_____   By: _____
                                 John C. Garvey
                                 Registration No. 28,807

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VERSION WITH MARKINGS TO SHOW CHANGES MADE

IN THE CLAIMS:

Please **AMEND** claim 6 as follows:

6. (ONCE AMENDED) The characteristic value identification method as claimed in [any one of claims 1 to 5] claim 1,wherein the third process includes[;] :

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

Please **ADD** the claims 19-22 as follows:

19. (NEW) The characteristic value identification method as claimed in claim 2, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

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20. (NEW) The characteristic value identification method as claimed in claim 3, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

21. (NEW) The characteristic value identification method as claimed in claim 4, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

22. (NEW) The characteristic value identification method as claimed in claim 5, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.